

# RX23W Group

## Tuning procedure of Bluetooth dedicated clock frequency

### Introduction

This document describes a tuning procedure of a clock frequency for RX23W Bluetooth® 5.0 (Core Specification v5.0) RF transceiver.

### Target Device

RX23W Group

Note: The contents of this document are provided as a reference and do not guarantee the signal quality in the system.

When designing the actual system, thoroughly evaluate the product in the overall system and apply these contents on your own responsibility.

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## 1. Overview

This document describes a tuning procedure to align Bluetooth dedicated clock frequency to 32MHz in RX23W group devices.

Because RX23W has load capacitors internally for the tuning of an oscillation frequency of 32MHz Bluetooth dedicated clock, the capacitors take contribution to reduce BoM cost and PCB area.

Bluetooth dedicated clock frequency varies not only due to RX23W device factor but also crystal oscillator and floating capacitance of PCB. Bluetooth dedicated clock frequency accuracy is specified within 50ppm including manufacturing irregularities, temperature drift, and aging deterioration of the crystal oscillator. If frequency tuning is not performed in PCB design, the PCB may not comply with the Bluetooth standard.

**Note:** An individual frequency tuning for each RX23W is unnecessary. However, the frequency tuning must be performed according to this document, when designing a new PCB, or changing the crystal oscillator model number or the PCB design around the oscillator.

### 1.1 Related documents

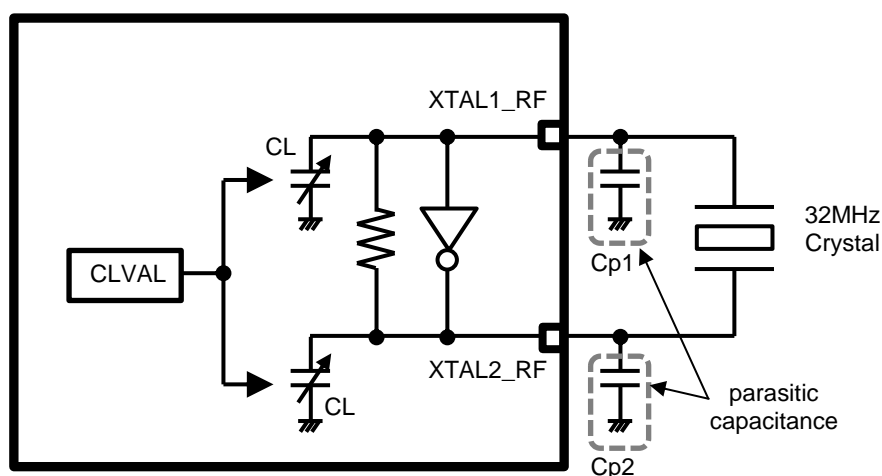
The following documents are related to this application note. Also refer to these documents when using this application note.

- RX23W User's Manual: Hardware (R01UH0823)
- Guidelines for Bluetooth Board Design (R01AN4534)
- Bluetooth Low Energy Protocol Stack Basic Package User's Manual (R01UW0205)

## 2. Bluetooth dedicated clock oscillator

Figure 2-1 shows circuitry of Bluetooth dedicated clock oscillator. The oscillator has two load capacitors (CL) internally for the tuning of an oscillation frequency of Bluetooth dedicated clock. The internal capacitors are connected to terminals XTAL1\_RF and XTAL2\_RF respectively. The capacitance of CL can be adjusted in the range of Table 2-1. The oscillation frequency error can be minimized with the appropriate capacitor setting (CLVAL).

The capacitance of line pattern between the crystal oscillator and RX23W or the parasitic capacitance of the pads for solder mount (Cp1, Cp2) will be factors of oscillation frequency variation. Therefore, the optimum capacitor setting will be vary depending on the PCB layout as well as the adopted crystal oscillator.



**Figure 2-1. Circuitry of Bluetooth dedicated clock oscillator.**

**Table 2-1. Capacitance range of frequency tuning (CL)**

Capacitance tuning range (Typ.)	Capacitance resolution (Typ.)
1.8pF~14.4pF	0.84pF (16 steps)

### 3. Frequency tuning procedure

This section describes a tuning procedure of Bluetooth dedicated clock frequency.

Firstly, get software for frequency tuning (refer 3.1). Next, build hardware setup(refer 3.2), and set RX23W to output mode of unmodulated signal (CW: Continuous Wave) from ANT port or clock signal from CLKOUT\_RF port using operation program for calibration (refer 3.3). Then seek an optimal setting of minimum frequency error according to the tuning flow (refer 3.4).

#### 3.1 Software

- RX23W firmware for frequency tuning
  - UART-HCI mode firmware
 

Download a “Bluetooth Low Energy protocol stack basic package for RX23W” from Renesas website.  
Then compile a UART-HCI mode firmware which can be executed in a measurement environment.
- Operation program for calibration
  - CLVALTune.exe
 

This software is included in “Bluetooth Low Energy protocol stack basic package for RX23W”.

#### 3.2 Hardware setup

When frequency tuning of Bluetooth dedicated clock, a high precision frequency measurement system in ppm order is necessary. Considering combinations of monitor ports and connections, there are three hardware setups. Select one of the hardware setups according to the PCB mount condition.

##### 3.2.1 Case of observing ANT output frequency with cable connection

In the setup of Figure 3-1, 2440MHz unmodulated signal is output from ANT port, and the signal frequency is observed with a coaxial cable connection. Because the high precision frequency measurement is needed, set the spectrum analyzer to the frequency count mode.

- Required environment
  - RX23W evaluation board (PCB)
  - Measuring instruments
    - Spectrum analyzer with frequency counter function (over 3GHz)
    - Coaxial cable
  - PC for evaluation
  - USB to UART cable

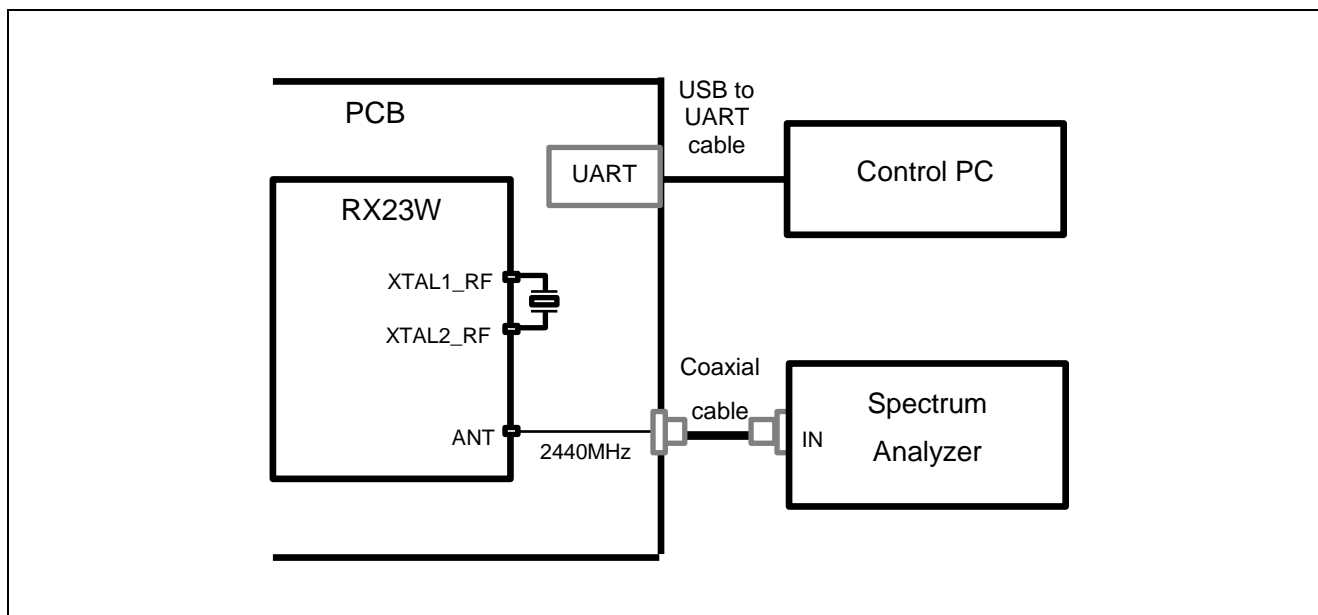


Figure 3-1. Measurement setup of ANT frequency (cable connection)

### 3.2.2 Case of observing ANT output frequency with wireless connection

In the setup of Figure 3-2, 2440MHz unmodulated signal is output from ANT port, and the signal frequency is observed with a wireless connection. Because the high precision frequency measurement is needed, set the spectrum analyzer to the frequency count mode.

When the wireless measurement setup is selected, measure the frequency in a noiseless environment not to immunity other 2.4GHz band signal. And bring close the antenna of RX23W up the antenna of the measuring instrument in order to enough input amplitude to the measuring instrument.

If the frequency measurement is unstable due to less input amplitude to the measuring instrument, solder a coaxial cable to signal line pattern of ANT directly and measure the frequency in the setup of 3.2.1.

- Required environment
  - RX23W evaluation board (PCB)
  - Measuring instruments
    - Spectrum analyzer with frequency counter function (over 3GHz)
    - Antenna for Bluetooth
  - PC for evaluation
  - USB to UART cable

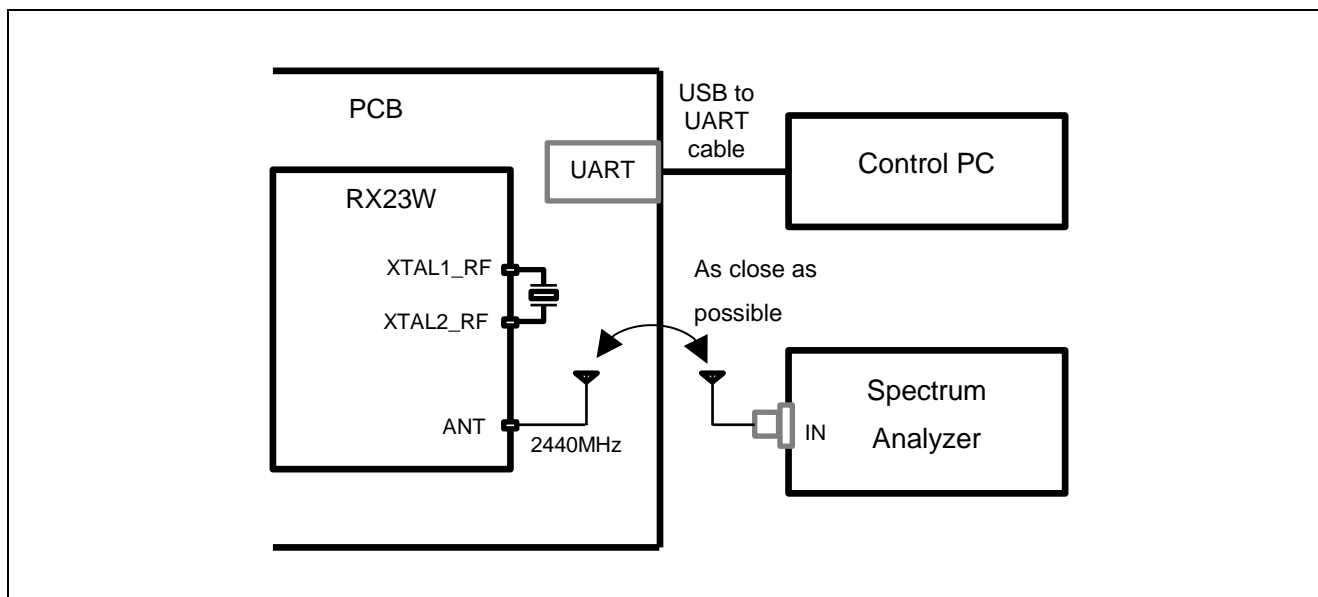


Figure 3-2. Measurement setup of ANT frequency (wireless connection)

### 3.2.3 Case of observing CLKOUT\_RF output frequency

In the setup of Figure 3-3, 4MHz clock signal is output from CLKOUT\_RF port, and the signal frequency is observed with the high precision universal frequency counter. This setup is effective when upper limit frequency of the measuring instrument is low. However, if the clock signal can't be output properly from CLKOUT\_RF port, the setup can't be used.

- Required environment
  - RX23W evaluation board (PCB)
  - Measuring instruments
    - High precision universal frequency counter
    - High impedance probe
  - PC for evaluation
  - USB to UART cable

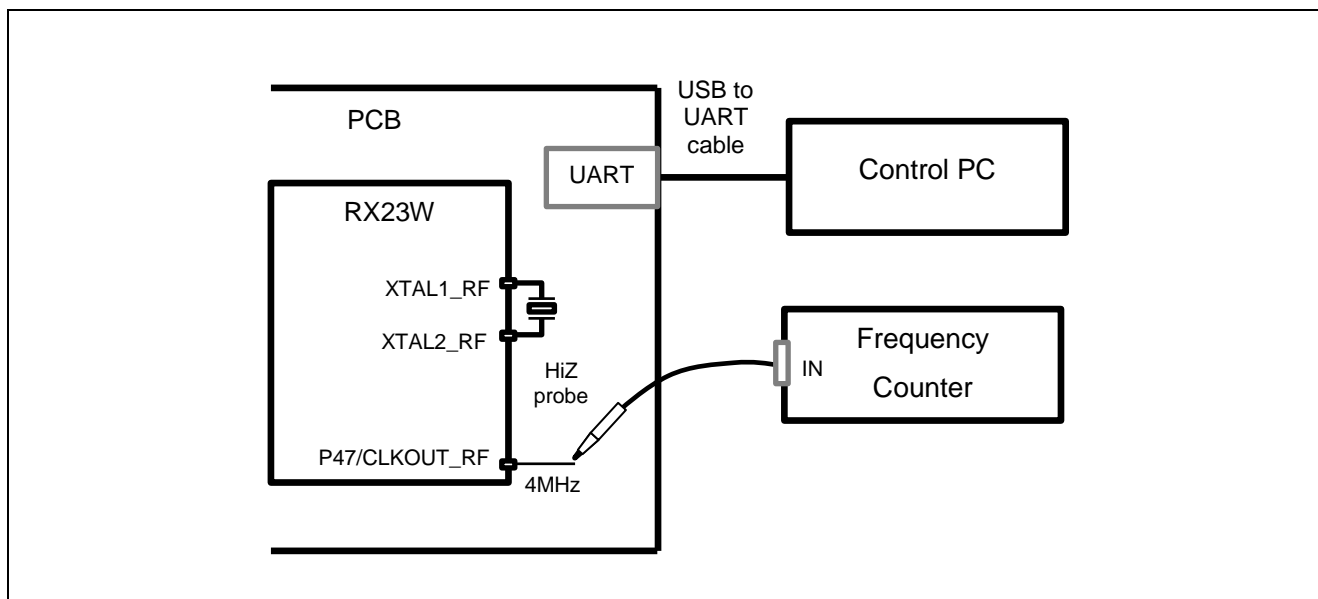


Figure 3-3. Measurement setup of CLKOUT\_RF frequency

### 3.3 Operation program for calibration

The operation program for calibration is a dedicated software for frequency tuning of Bluetooth dedicated clock. When using software, UART-HCI mode firmware which can be executed in the measurement environment is necessary.

On the operation program, capacitor setting for frequency tuning (CLVAL) can be changed and 4MHz clock output or 2440MHz unmodulated signal output can be switched.

Note: When a UART port doesn't exist in the measurement environment, this software can't be used. In this case, it is necessary to repeat choosing one from 16 embedded firmwares for CLVAL setting and writing the firmware to RX23W, until determine an optimum CLVAL setting by the frequency tuning.

#### 3.3.1 Case of observing ANT output frequency

Figure 3-4 shows the program setting in observing 2440MHz unmodulated signal from ANT port. The program setting is common for the cable and wireless connection.

COM port : Depends on PC configuration

Baudrate : Depends on UART-HCI mode firmware (default : 115200)

CLVAL : Capacitor setting for frequency tuning, select an arbitrary value from 0 to 15 (default : 5)

CLKOUT\_RF : Select "No output"

Continuous Wave Tx : Select "19ch (2440MHz)"

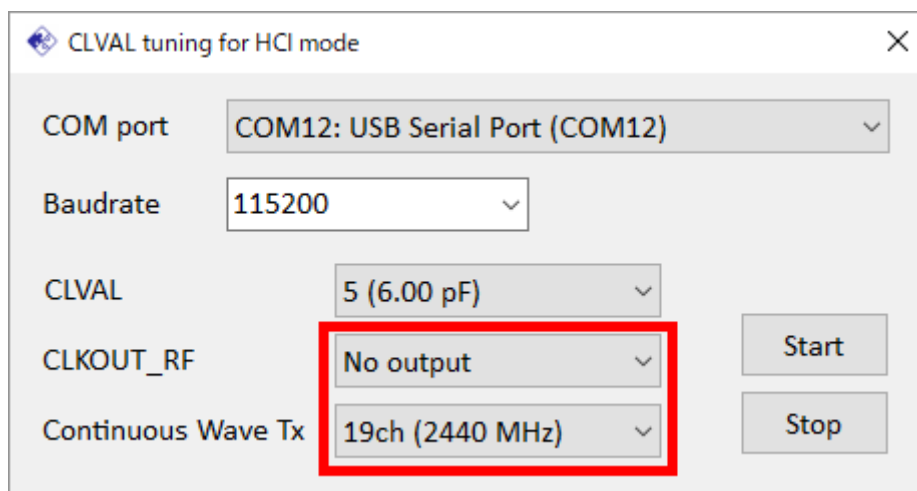


Figure 3-4. Program setting when frequency measurement on ANT port

### 3.3.2 Case of observing CLKOUT\_RF output frequency

Figure 3-5 shows the program setting in observing 4MHz clock signal from CLKOUT\_RF port. The program setting is common for the cable and wireless connection.

COM port : Depends on PC configuration

Baudrate : Depends on UART-HCI mode firmware (default : 115200)

CLVAL : Capacitor setting for frequency tuning, select an arbitrary value from 0 to 15 (default : 5)

CLKOUT\_RF : Select "4MHz output"

Continuous Wave Tx : Select "Disable"

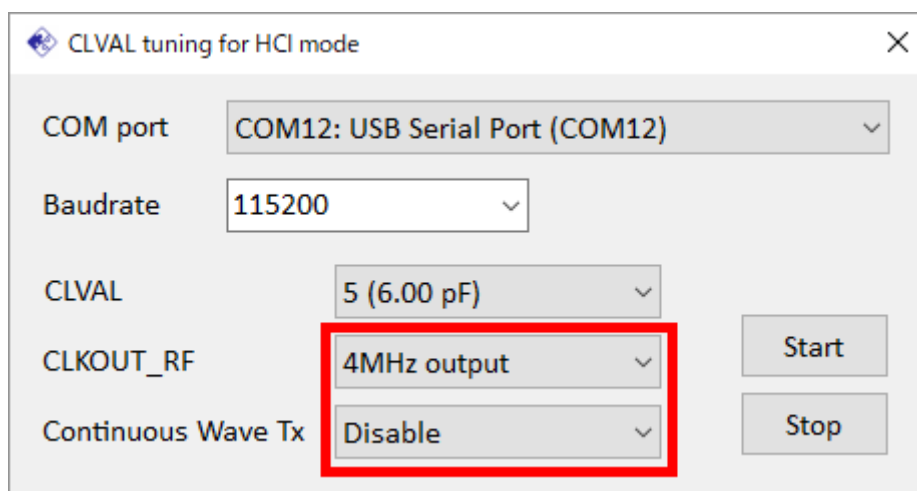


Figure 3-5. Program setting when frequency measurement on CLKOUT\_RF port



### 3.4 Tuning procedure of Bluetooth dedicated clock frequency

A tuning procedure of Bluetooth dedicated clock frequency to determine an optimum capacitor setting (CLVAL) is as follows:

1. Build a hardware setup and set the measuring instrument to frequency count mode.
2. Download a firmware for frequency tuning to RX23W.
3. Run an operation program for calibration.
4. Select the program setting corresponding to the hardware setup, and an arbitrary CLVAL setting.
5. Click "Start" button. A signal outputs from ANT or CLKOUT\_RF port.
6. Record the frequency count value on the measuring instrument display. Then click "Stop" button. The output signal from ANT or CLKOUT\_RF port will stop.
7. When the measured frequency is lower than target frequency which is 2440MHz on ANT port or 4MHz on CLKOUT\_RF port, change value of CLVAL to smaller. When the measured frequency is higher than target frequency, change value of CLVAL to larger.
8. Repeat steps from 5 to 7 until the difference between measurement and target frequency is minimized and determine an optimal CLVAL setting.

Set the determined CLVAL setting value by the procedure to the configuration parameter of Bluetooth Low Energy stack basic package in an application development. And build the application. Figure 3-6 shows an example of a description to configuration parameter.

```

/*****
Capacity adjustment of 32MHz crystal resonator.
0 to 15: Adjust according to board environment.
*****/
#define BLE_CFG_RF_CLVAL          (5)

```

Figure 3-6. Example of a description to configuration parameter

## 4. Crystal oscillator selection guide

### 4.1 Characteristic for crystal oscillator

Select the crystal oscillator model number based on the recommended parameters shown in Table 4-1.

Table 4-1. Recommended parameters of crystal oscillator

Parameter	Recommendation
Equivalent series resistance (ESR)	≤ 100ohm
Drive level	≤ 100uW
Load capacitance	≥ 5pF, ≤ 8pF

In addition, selecting a crystal oscillator with a small amount of frequency fluctuation for the load capacitance change, the requirement of the crystal oscillator frequency accuracy can be relaxed. The amount of frequency fluctuation for the load capacitance is different for each crystal oscillator, so please contact the crystal oscillator manufacturer for details.

## 4.2 Frequency accuracy requirement for crystal oscillator

This section explains the frequency accuracy requirement for the crystal oscillator. When selecting a crystal oscillator, make sure that the frequency accuracy of the crystal oscillator is within the required accuracy.

The way of thinking about the frequency accuracy requirement for the crystal oscillator is the following.

The factors of the Bluetooth dedicated clock frequency error can be classified into two: RX23W and crystal oscillator. The frequency accuracy requirement for the crystal oscillator is the value which can be obtained by subtracting the frequency error due to the RX23W from the required accuracy for the Bluetooth dedicated clock.

The frequency error based on RX23W are composed with initial adjustment error, manufacturing variation, temperature change and, aging change. These frequency error depends on the frequency fluctuation characteristic of the crystal oscillator for load capacitance change.

Table 4-2 shows an example of the frequency error budget. In this example, it is assumed which an optimum CL capacitance setting ( $CLVAL_{opt}$ ) is 6 and the frequency variation ( $\Delta F_{VAL}$ ) is  $\pm 8$  ppm when changing  $\pm 1$  step (0.84 pF) from  $CLVAL_{opt}$ .

The initial adjustment error when performing the frequency tuning procedure shown in Chapter 3 is expected to be up to  $0.5step \times \Delta F_{VAL} = 0.5 \times 8ppm = \pm 4$  ppm.

In addition, the total error due to manufacturing variation, temperature change, and aging change of RX23W, corresponds to up to  $0.22 \times CLVAL_{opt} = 0.22 \times 6 = 1.32step$  change. This change is translated to a frequency error of  $0.22 \times CLVAL_{opt} \times \Delta F_{VAL} = 0.22 \times 6 \times 8ppm = \pm 11$  ppm. From the above, the maximum frequency error due to RX23W is  $\pm 15$  ppm in total.

Here, the accuracy of the Bluetooth dedicated clock is specified within  $\pm 50$  ppm in the Bluetooth standard. Therefore, the frequency accuracy requirement for the crystal oscillator is within  $\pm 35$  ppm, including manufacturing variation, temperature change, and aging change.

**Table 4-2. Example of frequency error budget ( $CLVAL_{opt}=6$ )**

Parts	Error factor	Maximum error
RX23W	Initial tuning error	$\pm 4ppm$ <sup>(*)1</sup> (0.5 step)
	Summation of manufacturing variations, temperature changes, and aging change	$\pm 11ppm$ <sup>(*)1</sup> (1.32 step)
Crystal oscillator	Summation of manufacturing variations, temperature changes, and aging change	Requirement: within $\pm 35ppm$ <sup>(*)1</sup>
Total		within $\pm 50$ ppm <sup>(*)2</sup>

\*1) Assuming the frequency variation is  $\pm 8$  ppm when changing  $\pm 1$  step from optimum CL capacitance setting.

\*2) Frequency accuracy requirement of Bluetooth dedicated clock

### 4.3 List of crystal oscillators

Table 4-3 is a list of crystal oscillators enforced in matching measurement. For details of the matching, please contact each crystal oscillator manufacturer.

**Table 4-3. List of crystal oscillators**

Manufacturer	Parts number	SMD/Lead size code (in mm)	Frequency (MHz)	Frequency Tolerance (ppm)	Frequency Stability (ppm)	Equivalent Series Resistance (ohm)	Load Capacitance (pF)
NDK	NX1612SA-32.000MHZ-CHP-CIS-3	1612	32.00	+/-10	+/-20	Max 100	6
NDK	NX1210AB-32.000MHZ-CHP-CIX-3	1210	32.00	Total +/-30		Max 100	6
Kyocera	CX1612DB32000 A0WPNC1	1612	32.00	Total +/-25		Max 100	5
Kyocera	CX1210SB32000 B0GPJC1	1210	32.00	Total +/-30		Max 80	6

## 5. Reference

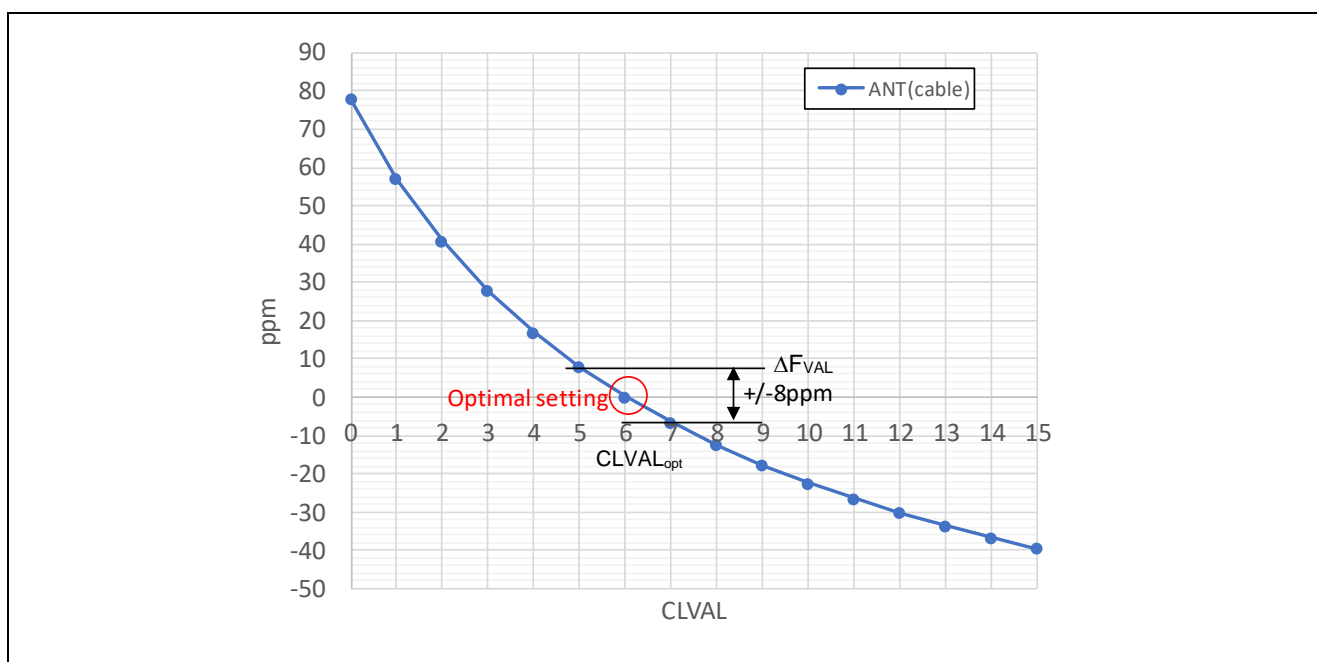
### 5.1 Example of frequency tuning

An example is shown in which the ANT output signal frequency is observed with a cable connection using the configuration in Table 5-1, and the frequency tuning of the Bluetooth dedicated clock is performed.

**Table 5-1. Environment of frequency tuning**

Item	Composition content
DUT	RX23W 56pin QFN
Crystal oscillator	CX1612DB32000A0WPNC1 (Kyocera) Equivalent series resistance (ESR) : Max 100ohm Load capacitance: 5pF Frequency error : +/-25ppm (including temperature variation)
Measuring instrument	E4440A PSA spectrum analyzer (Keysight)
Monitor port	ANT with cable connection

The frequency error plot changing the CLVAL setting is shown in Figure 5-1. According to the plot, it can be seen that CLVAL setting (CLVAL<sub>opt</sub>) which gives minimum frequency error is 6. And the oscillation frequency change ( $\Delta F_{VAL}$ ) is +/-8 ppm when the CLVAL setting is +/- 1step changed from CLVAL<sub>opt</sub>.



**Figure 5-1. Frequency error versus CLVAL setting**

Figure 5-2 is a frequency count display when CLVAL is set to 6 in this frequency tuning example. The frequency count value is 2439.9985MHz and initial frequency tuning error is  $(2439.9985 - 2440) / 2440 = -0.6\text{ppm}$ .

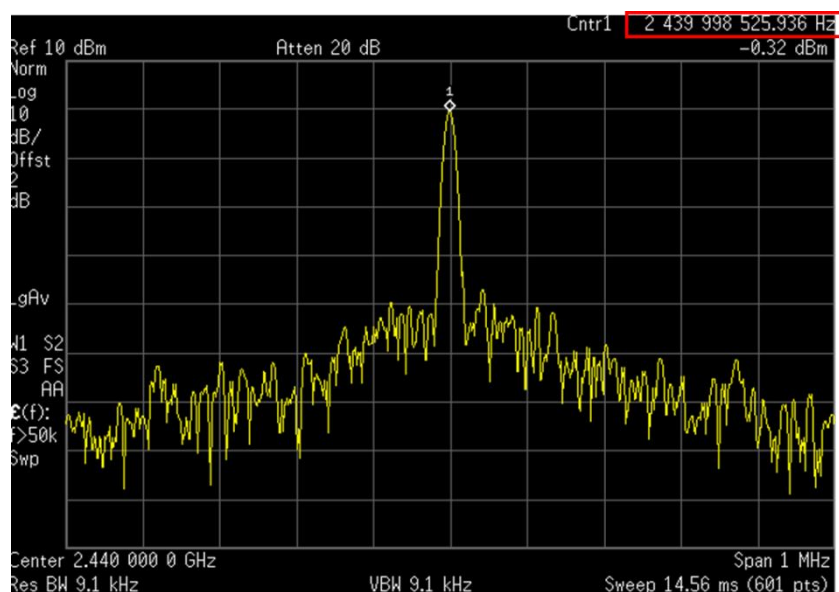


Figure 5-2. E4440A frequency count display (CLVAL=6)

With the optimum CLVAL setting ( $CLVAL_{opt}=6$ ), the frequency change per step ( $\pm 8$  ppm), and the initial tuning error ( $-0.6$  ppm), the frequency accuracy requirement for the crystal oscillator can be estimated by based on the explanation shown in section 4.2.

$$-50\text{ppm} + 0.6\text{ppm} + 0.22 \times 6 \times 8\text{ppm} \leq \text{required accuracy} \leq +50\text{ppm} + 0.6\text{ppm} - 0.22 \times 6 \times 8\text{ppm}$$

$$\Leftrightarrow -38.8\text{ppm} \leq \text{required accuracy} \leq +40.0\text{ppm}$$

Because the nominal frequency error ( $\pm 25$  ppm) of the crystal oscillator (CX1612DB32000A0WPNC1) is within the required accuracy, the crystal oscillator on this RX23W evaluation board can support the Bluetooth standard on the viewpoint of frequency accuracy.

**Revision History**

Rev.	Date	Description	
		Page	Summary
1.00	Jun.24.19	—	First edition issued

# General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

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Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

## 2. Processing at power-on

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## 3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

## 4. Handling of unused pins

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## 5. Clock signals

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## 6. Voltage application waveform at input pin

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